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| <b>Search Notes</b><br> | <b>Application/Control No.</b><br>10622294 | <b>Applicant(s)/Patent Under Reexamination</b><br>CHOWN, DAVID |
|  | <b>Examiner</b><br>Liu, Li                 | <b>Art Unit</b><br>2613  |

| SEARCHED |                               |                           |          |
|----------|-------------------------------|---------------------------|----------|
| Class    | Subclass                      | Date                      | Examiner |
| 372      | 102                           | 08/03/2006                | LL       |
| 398      | 41-43, 152, 129, 58, 122, 125 | 08/03/2006,<br>02/08/2007 | LL       |
| 385      | 12, 24, 93, 49                | 08/03/2006,<br>02/08/2007 | LL       |
| 250      | 25                            | 08/03/2006                | LL       |

| SEARCH NOTES                                |                           |          |
|---|---------------------------|----------|
| Search Notes                                | Date                      | Examiner |
| EAST  |                           |          |
| USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB | 08/03/2006,<br>02/08/2007 | LL       |
| Google                                      | 08/03/2006                | LL       |
| IEEE  | 08/03/2006                | LL       |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |